

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

IN RE APPLICATION OF: Masayuki JYUMONJI, et al.

SERIAL NO: New Application

GAU:

FILED: Herewith

EXAMINER:

FOR: SEMICONDUCTOR DEVICE, ANNEALING METHOD, ANNEALING APPARATUS AND DISPLAY APPARATUS

**INFORMATION DISCLOSURE STATEMENT UNDER 37 CFR 1.97**

COMMISSIONER FOR PATENTS  
ALEXANDRIA, VIRGINIA 22313

SIR:

Applicant(s) wish to disclose the following information.

**REFERENCES**

- ☒ The applicant(s) wish to make of record the references listed on the attached form PTO-1449. Copies of the listed references are attached, where required, as are either statements of relevancy or any readily available English translations of pertinent portions of any non-English language references.
- ☐ A check or credit card payment form is attached in the amount required under 37 CFR §1.17(p).

**RELATED CASES**

- ☐ Attached is a list of applicant's pending application(s) or issued patent(s) which may be related to the present application. A copy of the patent(s), together with a copy of the claims and drawings of the pending application(s) is attached along with PTO 1449.
- ☐ A check or credit card payment form is attached in the amount required under 37 CFR §1.17(p).

**CERTIFICATION**

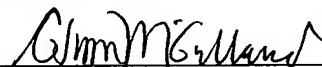
- ☐ Each item of information contained in this information disclosure statement was first cited in a communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of this statement.
- ☐ No item of information contained in this information disclosure statement was cited in a communication from a foreign patent office in a counterpart foreign application or, to the knowledge of the undersigned, having made reasonable inquiry, was known to any individual designated in 37 CFR §1.56(c) more than three months prior to the filing of this statement.

**DEPOSIT ACCOUNT**

- ☒ Please charge any additional fees for the papers being filed herewith and for which no check or credit card payment is enclosed herewith, or credit any overpayment to deposit account number 15-0030. A duplicate copy of this sheet is enclosed.

Respectfully submitted,

OBLON, SPIVAK, McCLELLAND,  
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DOCKET NO.: 243111US2

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**STATEMENT OF RELEVANCY**

**Reference AW of Form PTO-1449:**

This document is disclosed in the body of the specification.

Form PTO 1449  
(Modified)U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICE

ATTY DOCKET NO.

243111US2

SERIAL NO.

New Application

## LIST OF REFERENCES CITED BY APPLICANT

APPLICANT

Masayuki JYUMONJI, et al.

FILING DATE

Herewith

GROUP

## U.S. PATENT DOCUMENTS

| EXAMINER<br>INITIAL |    | DOCUMENT<br>NUMBER | DATE | NAME | CLASS | SUB<br>CLASS | FILING DATE<br>IF APPROPRIATE |
|---------------------|----|--------------------|------|------|-------|--------------|-------------------------------|
|                     | AA |                    |      |      |       |              |                               |
|                     | AB |                    |      |      |       |              |                               |
|                     | AC |                    |      |      |       |              |                               |
|                     | AD |                    |      |      |       |              |                               |
|                     | AE |                    |      |      |       |              |                               |
|                     | AF |                    |      |      |       |              |                               |
|                     | AG |                    |      |      |       |              |                               |
|                     | AH |                    |      |      |       |              |                               |
|                     | AI |                    |      |      |       |              |                               |
|                     | AJ |                    |      |      |       |              |                               |
|                     | AK |                    |      |      |       |              |                               |
|                     | AL |                    |      |      |       |              |                               |
|                     | AM |                    |      |      |       |              |                               |
|                     | AN |                    |      |      |       |              |                               |

## FOREIGN PATENT DOCUMENTS

|  |    | DOCUMENT<br>NUMBER | DATE     | COUNTRY                       | TRANSLATION |    |
|--|----|--------------------|----------|-------------------------------|-------------|----|
|  |    |                    |          |                               | YES         | NO |
|  | AO | 2002-151407        | 05/24/02 | Japan (with English abstract) |             | X  |
|  | AP | 2002-280309        | 09/27/02 | Japan (with English abstract) |             | X  |
|  | AQ | 2002-313725        | 10/25/02 | Japan (with English abstract) |             | X  |
|  | AR | 2002-313726        | 10/25/02 | Japan (with English abstract) |             | X  |
|  | AS |                    |          |                               |             |    |
|  | AT |                    |          |                               |             |    |
|  | AU |                    |          |                               |             |    |
|  | AV |                    |          |                               |             |    |

## OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

|  |    |                                                                                                                                                                                                                                                   |  |  |  |                                                                  |
|--|----|---------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------------|--|--|--|------------------------------------------------------------------|
|  | AW | "FLAT PANEL DISPLAY", 1999, Nikkei Micro Device, Supplemental Edition, Nikkei BP Co., Ltd., 1998, pgs. 132 - 139.                                                                                                                                 |  |  |  |                                                                  |
|  | AX | M. JYUMONJI, et al., "HIGH-RESOLUTION BEAM PROFILER - NEW POWERFUL TOOL FOR ENGINEERING LATERALLY-GROWN GRAIN MORPHOLOGY -", AMDp-17, (Late-News Paper), IDW '02, pgs. 1387 - 1388.                                                               |  |  |  |                                                                  |
|  | AY | Ryoichi ISHIHARA, et al., "EFFECTS OF LIGHT PULSE DURATION ON EXCIMER-LASER CRYSTALLIZATION CHARACTERISTICS OF SILICON THIN FILMS", Jpn. J. Appl. Phys. Vol. 34, Part 1, No. 4A, April 1995, pgs. 1759 - 1764.                                    |  |  |  |                                                                  |
|  | AZ | Masayuki JYUMONJI, et al., "DOUBLE-PULSE METHOD FOR ENLARGING LATERAL GRAIN GROWTH OF EXCIMER LASER ANNEALED POLY-Si THIN FILMS", The Institute of Physical and Chemical Research, NEC Res. & Develop., Vol 42, No. 3, July 2001, pgs. 272 - 276. |  |  |  | <input type="checkbox"/> Additional References sheet(s) attached |

Examiner

Date Considered

\*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.